

**Notic of R ferences Cited**

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

MARUYAMA ET AL

Examiner

Edward Wojciechowicz

Art Unit

2815

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	B	US-6258459	07-2001	Noguchi et al	257/295
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	D	US-			
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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